Supporting Information



Figure S1. The cross sectional SEM image of Ni film chemical electrodeposited without post annealing.



Figure S2. XRD patterns of p-Ni/NiO template annealed at 600 °C for 5 h and Ni before annealing.



Figure S3. Schematic of change on microstructure of p-Ni/NiO templates annealed at 500°C, 600 °C, 800 °C for 5 h and Ni before annealing (a) without OP addition and (b) OP (0.01%) addition in the bath.



Figure S4. SEM images of p-Ni/NiO templates after a) 1, b) 5, c) 10, and d) 20 cycles of microarrays fabrication and demolding.



Figure S5. Comparison of water contact angles on microarrays with different morphologies: a) L-AR($133^{\circ}\pm1^{\circ}$) b) H-AR($140^{\circ}\pm1^{\circ}$) c) RM($150^{\circ}\pm1^{\circ}$) d) GFMI: $155^{\circ}\pm1^{\circ}$) and e) GFMII ($153^{\circ}\pm1^{\circ}$).